

December 2000



FQD5N20L / FQU5N20L

200V LOGIC N-Channel MOSFET

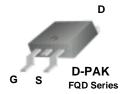
General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

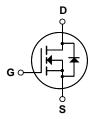
This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation modes. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, and motor control.

Features

- 3.8A, 200V, $R_{DS(on)} = 1.2\Omega @V_{GS} = 10 \text{ V}$
- Low gate charge (typical 4.8 nC)
- Low Crss (typical 6.0 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- Low level gate drive requirement allowing direct operation from logic drivers







Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD5N20L / FQU5N20L	Units	
V _{DSS}	Drain-Source Voltage		200	V	
I _D	Drain Current - Continuous (T _C = 25	°C)	3.8	Α	
	- Continuous (T _C = 10	0°C)	2.4	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	15.2	А	
V_{GSS}	Gate-Source Voltage		± 20	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	60	mJ	
I _{AR}	Avalanche Current	(Note 1)	3.8	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	3.7	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P _D	Power Dissipation (T _A = 25°C) *		2.5	W	
	Power Dissipation (T _C = 25°C)		37	W	
	- Derate above 25°C		0.29	W/°C	
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	200			V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.18		V/°C
I _{DSS}	Zero Cota Valta de Dueia Comunat	V _{DS} = 200 V, V _{GS} = 0 V			1	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 160 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.0	V
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 1.9 \text{ A}$ $V_{GS} = 5 \text{ V}, I_D = 1.9 \text{ A}$ (Note 4)		0.94	1.2	Ω
20(0)	On-Resistance			0.98	1.25	
9 _{FS}	Forward Transconductance	V _{DS} = 30 V, I _D = 1.9 A		3.35		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		250 40 6	325 50 8	pF pF pF
	ing Characteristics					'
t _{d(on)}	Turn-On Delay Time			9	25	ns
t _r	Turn-On Rise Time	$V_{DD} = 100 \text{ V}, I_D = 4.5 \text{ A},$		90	190	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$ (Note 4, 5)		15	40	ns
t _f	Turn-Off Fall Time			50	110	ns
Q _g	Total Gate Charge	V _{DS} = 160 V, I _D = 4.5 A,		4.8	6.2	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V} \qquad \text{(Note 4, 5)}$		1.2		nC
Q _{gd}	Gate-Drain Charge	- 65		2.4		nC
	Source Diode Characteristics ar	nd Maximum Ratings				I.
I _S	Maximum Continuous Drain-Source Diode Forward Current				3.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				15.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 3.8 \text{ A}$			1.5	V
OD					i e	i e
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 4.5 \text{ A}, \qquad \text{(Note 4)}$		95		ns

- $\label{eq:Notes:Notes:Notes:1} \begin{tabular}{ll} \textbf{Notes:} \\ \textbf{1.} & \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature } \textbf{2.} \ L = 6.2 \text{mH, } \ |_{A_S} = 3.8 \text{A, } \ |_{DD} = 50\text{V, } \ R_G = 25 \ \Omega. \ \text{Starting } \ T_J = 25^{\circ}\text{C} \\ \textbf{3.} \ |_{SD} \le 4.5 \text{A, } \ \text{di/dt} \le 300 \text{A/µs, } \ V_{DD} \le BV_{DSS,} \ \text{Starting } \ T_J = 25^{\circ}\text{C} \\ \textbf{4.} & \textbf{Pulse Test: Pulse width} \le 300 \text{µs, } \ \text{Duty cycle} \le 2\% \\ \textbf{5.} & \textbf{Essentially independent of operating temperature} \\ \end{tabular}$

Typical Characteristics

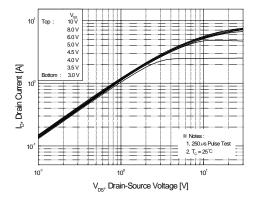


Figure 1. On-Region Characteristics

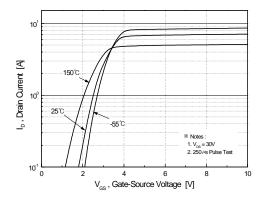


Figure 2. Transfer Characteristics

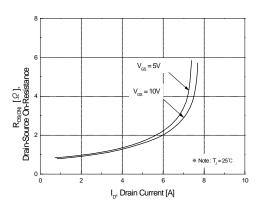


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

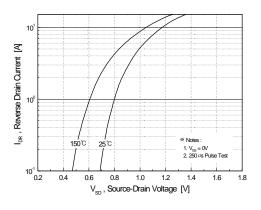


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

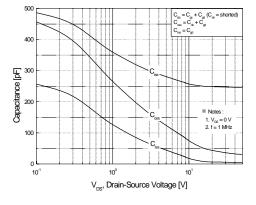


Figure 5. Capacitance Characteristics

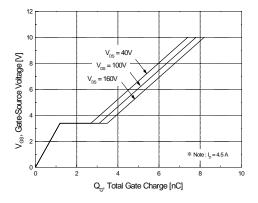


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

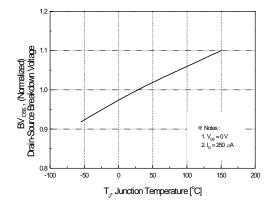
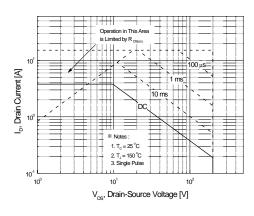


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



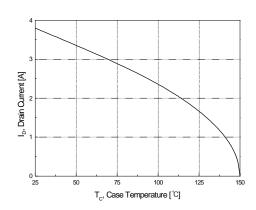


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

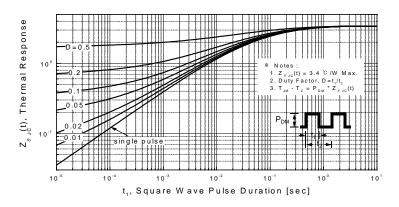
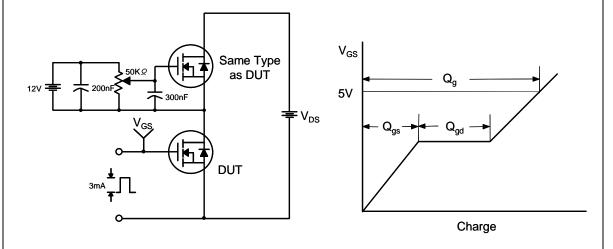


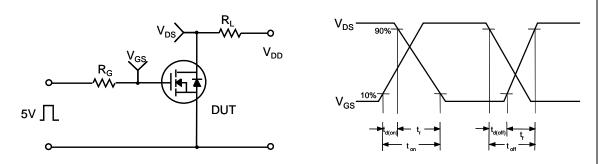
Figure 11. Transient Thermal Response Curve

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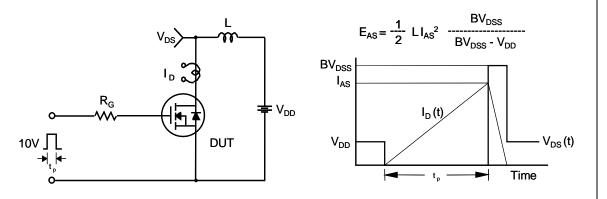
Gate Charge Test Circuit & Waveform



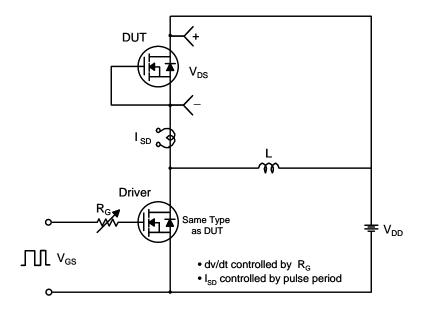
Resistive Switching Test Circuit & Waveforms

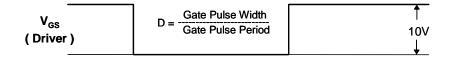


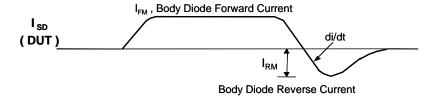
Unclamped Inductive Switching Test Circuit & Waveforms

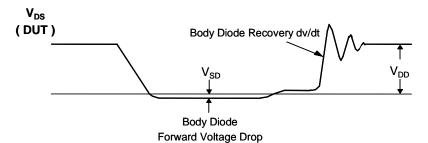


Peak Diode Recovery dv/dt Test Circuit & Waveforms

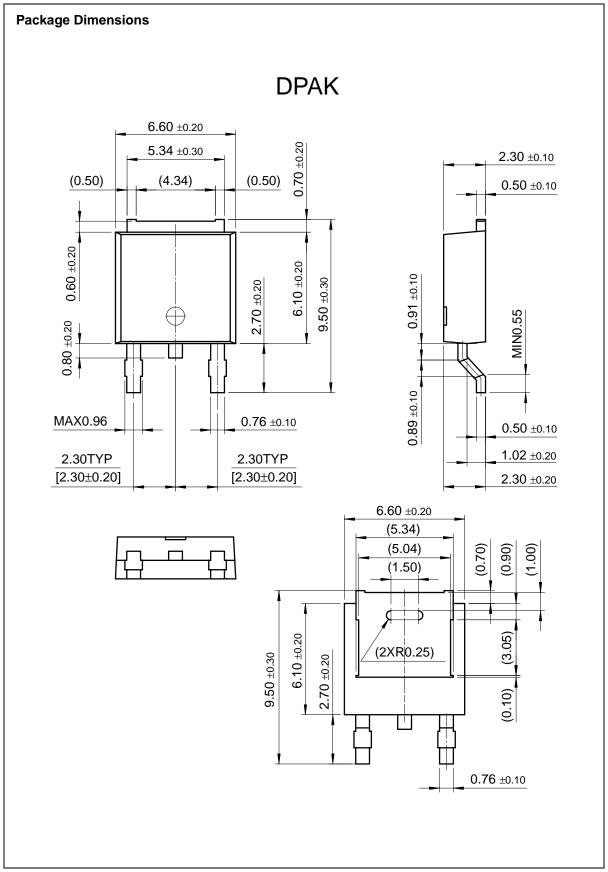






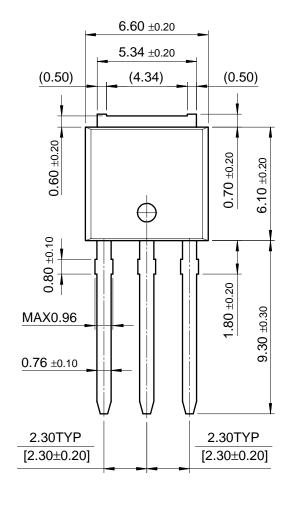


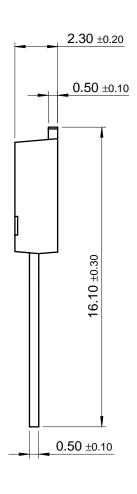
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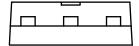




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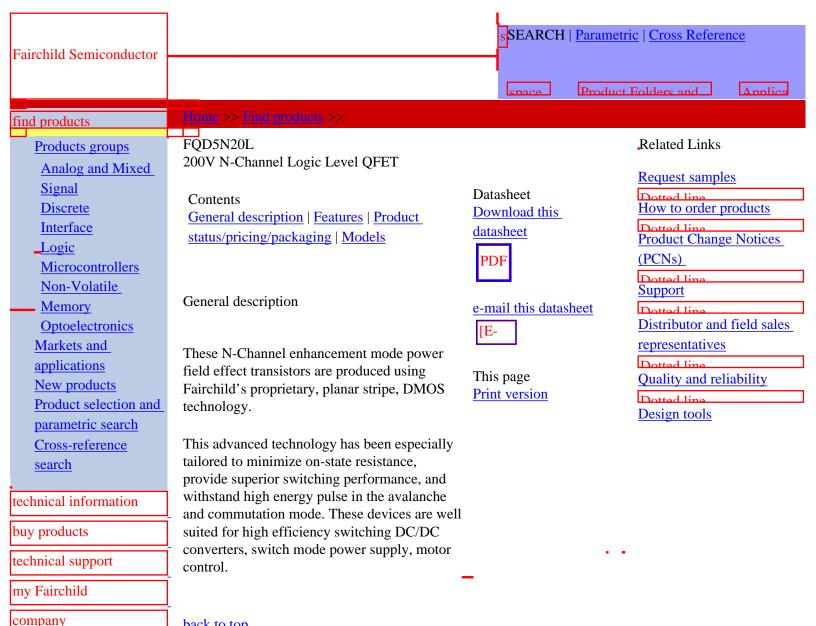
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PRODUCT STATUS DEFINITIONS

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Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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Features

- 3.8A, 200V, $R_{DS(on)} = 1.2\Omega$ @ $V_{GS} = 10V$
- Low gate charge (typical 4.8nC)
- Low Crss (typical 6.0pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Low level gate drive requirement allowing direct operation from logic drivers

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method
FQD5N20LTM	Full Production	\$0.365	TO-252(DPAK)	2	TAPE REEL
FQD5N20LTF	Full Production	\$0.365	TO-252(DPAK)	2	TAPE REEL

^{* 1,000} piece Budgetary Pricing

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Models

Package & leads Condition		Temperature range	Software version	Revision date	
PSPICE					
TO-252(DPAK)-2	Electrical	-55°C to 150°C	9.2	Sep 3, 2001	

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